



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application

Inventor(s): Christopher J. Barbazette, et al.

Application No.: 10/618,313

Confirm. No.: 4770

Filed: July 10, 2003

Title: Data Collection and Diagnostic  
System for a Semiconductor  
Fabrication Facility


PATENT APPLICATION

Art Unit: 2121

Examiner: Chang, Sunray

**CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8**

I hereby certify that this correspondence is being deposited in the United States Postal Service with sufficient postage as first class mail in an envelope addressed to, Non-Fee Amendment Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on September 10, 2007.

  
Michael L. Gencarella, Reg. No. 44,703  
Signature Date: September 10, 2007

**AMENDMENT**

Mail Stop: Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to Office Action mailed on July 10, 2007. Please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 5 of this paper.

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